# MOSFET – Power, P-Channel, ChipFET -20 V, -4.9 A

#### Features

- Low R<sub>DS(on)</sub> for Higher Efficiency
- Logic Level Gate Drive
- Miniature ChipFET Surface Mount Package Saves Board Space
- Pb–Free Package is Available

#### Applications

• Power Management in Portable and Battery–Powered Products; i.e., Cellular and Cordless Telephones and PCMCIA Cards

		,		
Rating	Symbol	5 secs	Steady State	Unit
Drain-Source Voltage	V <sub>DS</sub>	-2	20	V
Gate-Source Voltage	V <sub>GS</sub>	±	12	V
Continuous Drain Current $(T_J = 150^{\circ}C)$ (Note 1) $T_A = 25^{\circ}C$ $T_A = 85^{\circ}C$	ID	-4.9 -3.5	-3.6 -2.6	A
Pulsed Drain Current	I <sub>DM</sub>	±	15	Α
Continuous Source Current (Note 1)	۱ <sub>S</sub>	-4.9	-3.6	Α
$\begin{array}{l} \mbox{Maximum Power Dissipation (Note 1)} \\ T_A = 25^\circ C \\ T_A = 85^\circ C \end{array}$	P <sub>D</sub>	2.5 1.3	1.3 0.7	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	–55 to	o +150	°C

MAXIMUM RATINGS (T<sub>A</sub> = 25°C unless otherwise noted)

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

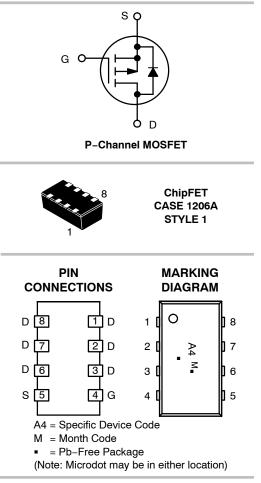
1. Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.27 in sq [1 oz] including traces).



# **ON Semiconductor®**

#### http://onsemi.com

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX
–20 V	56 mΩ @ −4.5	-4.9 A



#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NTHS5443T1	ChipFET	3000/Tape & Reel
NTHS5443T1G	ChipFET (Pb-Free)	3000/Tape & Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### **THERMAL CHARACTERISTICS**

Characteristic	Symbol	Тур	Max	Unit
Maximum Junction–to–Ambient (Note 2) t ≤ 5 s Steady State	$R_{ heta JA}$	40 80	50 95	°C/W
Maximum Junction-to-Foot (Drain) Steady State	$R_{ extsf{ heta}JF}$	15	20	°C/W

### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = $25^{\circ}C$ unless otherwise noted)

Characteristic Symbol		Test Condition	Min	Тур	Max	Unit
Static		•				
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}$ = $V_{GS}$ , $I_D$ = -250 $\mu$ A	-0.6			V
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS}$ = 0 V, $V_{GS}$ = ±12 V			±100	nA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DS} = -16 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			-1.0	μA
		$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 85^{\circ}\text{C}$			-5.0	
On-State Drain Current (Note 3)	I <sub>D(on)</sub>	$V_{DS}$ $\leq$ –5.0 V, $V_{GS}$ = –4.5 V	-15			А
Drain-Source On-State Resistance (Note 3)	r <sub>DS(on)</sub>	$V_{GS}$ = -4.5 V, I_D = -3.6 A $V_{GS}$ = -3.6 V, I_D = -3.3 A		0.056 0.065	0.065 0.074	Ω
		$V_{GS}$ = -2.5 V, I <sub>D</sub> = -2.7 A		0.095	0.110	
Forward Transconductance (Note 3)	9 <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -3.6 A		10		S
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	I <sub>S</sub> = -1.1 A, V <sub>GS</sub> = 0 V		-0.8	-1.2	V
Dynamic (Note 4)		•		-		
Total Gate Charge	Q <sub>G</sub>			7.5	12	nC
Gate-Source Charge	Q <sub>GS</sub>	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = -4.5 V, I <sub>D</sub> = -3.6 A		0.9	2.8	1
Gate-Drain Charge	Q <sub>GD</sub>			2.2	-	1
Turn–On Delay Time	t <sub>d(on)</sub>			8.5	13	ns
						-

 $\begin{array}{l} V_{DD} = -10 \text{ V}, \text{ } \text{R}_{L} = 10 \ \Omega \\ \text{I}_{D} \ \cong \ -1.0 \text{ } \text{A}, \text{ } \text{V}_{GEN} = -4.5 \text{ V}, \\ \text{ } \text{ } \text{R}_{G} = 6 \ \Omega \end{array}$ 

 $I_F = -1.1 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}$ 

14

38

30

30

21

57

45

60

ns

t<sub>rr</sub> Surface Mounted on FR4 Board using 1 in sq pad size (Cu area = 1.27 in sq [1 oz] including traces).
 Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Guaranteed by design, not subject to production testing.

t<sub>r</sub>

t<sub>d(off)</sub>

t<sub>f</sub>

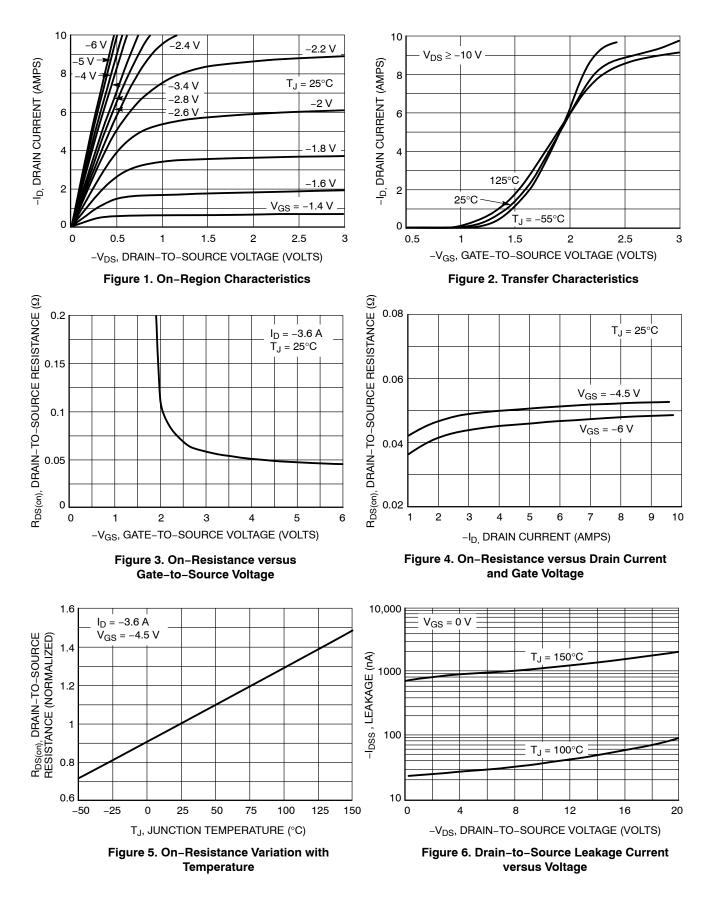
Source-Drain Reverse Recovery Time

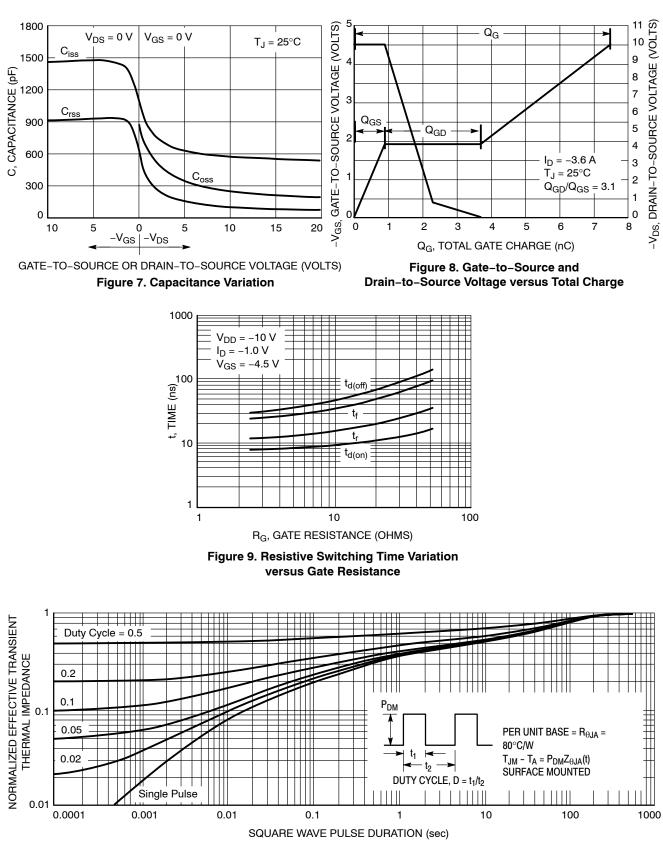
Rise Time

Fall Time

Turn-Off Delay Time

#### **TYPICAL ELECTRICAL CHARACTERISTICS**



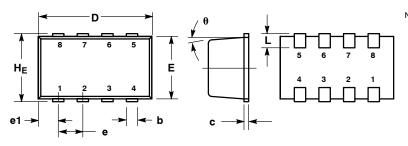


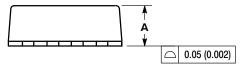
#### **TYPICAL ELECTRICAL CHARACTERISTICS**



#### **PACKAGE DIMENSIONS**

#### ChipFET™ CASE 1206A-03 ISSUE G



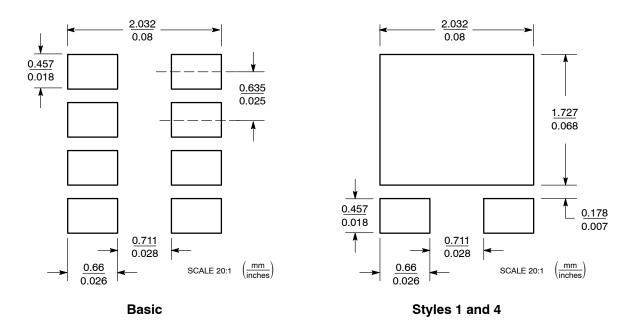


- NOTES:
  DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
  MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE.
  LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM.
  DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS.
  NO MOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α	1.00	1.05	1.10	0.039	0.041	0.043
b	0.25	0.30	0.35	0.010	0.012	0.014
с	0.10	0.15	0.20	0.004	0.006	0.008
D	2.95	3.05	3.10	0.116	0.120	0.122
E	1.55	1.65	1.70	0.061	0.065	0.067
е	0.65 BSC			0.025 BSC		
e1	0.55 BSC			0.022 BSC		
L	0.28	0.35	0.42	0.011	0.014	0.017
HE	1.80	1.90	2.00	0.071	0.075	0.079
θ	5° NOM			5° NOM		

STYLE 1: PIN 1. DRAIN 2. DRAIN 3. DRAIN 4. GATE 5. SOURCE 6. DRAIN 7. DRAIN 8. DRAIN

**SOLDERING FOOTPRINT\*** 



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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